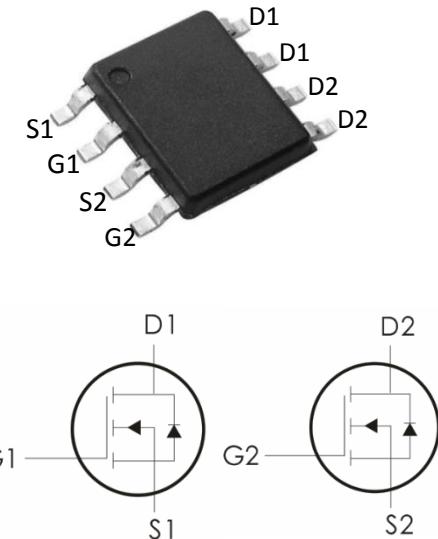


Description:

This N-Channel MOSFET uses advanced trench technology and design to provide excellent $R_{DS(on)}$ with low gate charge. It can be used in a wide variety of applications.

Features:

- 1) $V_{DS}=30V, I_D=10A, R_{DS(ON)}<10m\Omega @ V_{GS}=10V$
- 2) Low gate charge.
- 3) Green device available.
- 4) Advanced high cell density trench technology for ultra low $R_{DS(ON)}$.
- 5) Excellent package for good heat dissipation.



Absolute Maximum Ratings: ($T_A=25^\circ C$ unless otherwise noted)

Symbol	Parameter	Ratings	Units
V_{DS}	Drain-Source Voltage	30	V
V_{GS}	Gate-Source Voltage	± 20	V
I_D	Drain Current – Continuous ($T_A=25^\circ C$) ¹	10	A
	Drain Current – Continuous ($T_A=100^\circ C$) ¹	7	
I_{DM}	Drain Current – Pulsed ²	36	
E_{AS}	Single Pulse Avalanche Energy ³	24.2	mj
I_{AS}	Avalanche Current	22	A
P_D	Power Dissipation ($T_A=25^\circ C$) ⁴	1.5	W
T_J, T_{STG}	Operating and Storage Junction Temperature Range	-55 to +150	°C

Thermal Characteristics:

Symbol	Parameter	Max	Units
R_{eJC}	Thermal Resistance,Junction to Case ¹	25	°C/W
R_{eJA}	Thermal Resistance,Junction to Ambient ¹	85	

Electrical Characteristics: ($T_A=25^\circ\text{C}$ unless otherwise noted)

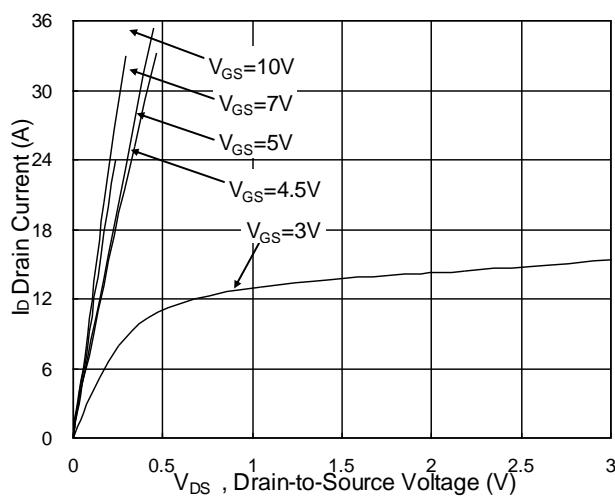
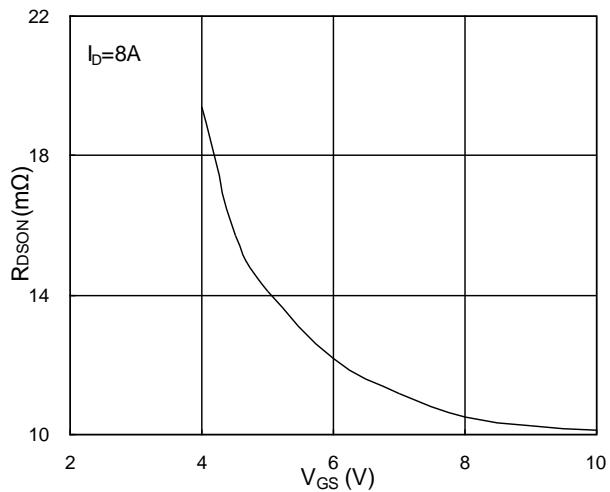
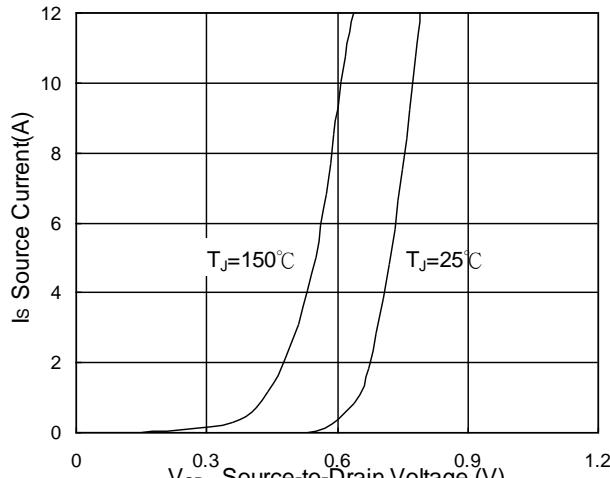
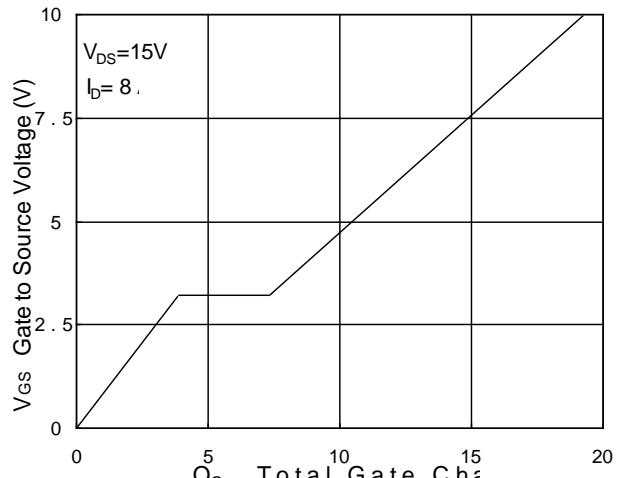
Symbol	Parameter	Conditions	Min	Typ	Max	Units
Off Characteristics						
BV_{DSS}	Drain-Source Breakdown Voltage	$V_{\text{GS}}=0\text{V}, I_D=250 \mu\text{A}$	30	---	---	V
I_{DSS}	Drain-Source Leakage Current	$V_{\text{DS}}=150\text{V}, V_{\text{GS}}=0\text{V}$	---	---	1	μA
I_{GSS}	Gate-Source Leakage Current	$V_{\text{GS}}=\pm 20\text{V}, V_{\text{DS}}=0\text{V}$	---	---	± 100	nA
On Characteristics³						
$V_{\text{GS}(\text{th})}$	GATE-Source Threshold Voltage	$V_{\text{GS}}=V_{\text{DS}}, I_D=250 \mu\text{A}$	1.2	1.5	2.5	V
$R_{\text{DS}(\text{ON})}$	Static Drain-Source On Resistance ²	$V_{\text{GS}}=10\text{V}, I_D=8\text{A}$	---	9	10	$\text{m } \Omega$
		$V_{\text{GS}}=4.5\text{V}, I_D=6\text{A}$	---	12	18	
G_{FS}	Forward Transconductance	$V_{\text{DS}}=5\text{V}, I_D=8\text{A}$	---	24	---	S
Dynamic Characteristics						
C_{iss}	Input Capacitance	$V_{\text{DS}}=15\text{V}, V_{\text{GS}}=0\text{V}, f=1\text{MHz}$	---	940	1316	pF
C_{oss}	Output Capacitance		---	131	183	
C_{rss}	Reverse Transfer Capacitance		---	109	153	
Switching Characteristics						
$t_{\text{d(on)}}$	Turn-On Delay Time	$V_{\text{DS}}=15\text{V}, R_{\text{GEN}}=1.5 \Omega, V_{\text{GS}}=10\text{V}$ $I_D=8\text{A}$	---	4.2	8.4	ns
t_r	Rise Time		---	8.2	15	ns
$t_{\text{d(off)}}$	Turn-Off Delay Time		---	31	62	ns
t_f	Fall Time		---	4	8	ns
Q_g	Total Gate Charge	$V_{\text{GS}}=4.5\text{V}, V_{\text{DS}}=15\text{V}, I_D=8\text{A}$	---	9.63	13.5	nC
Q_{gs}	Gate-Source Charge		---	3.88	5.4	nC
Q_{gd}	Gate-Drain "Miller" Charge		---	3.44	4.8	nC
Drain-Source Diode Characteristics						
V_{SD}	Source-Drain Diode Forward Voltage ²	$V_{\text{GS}}=0\text{V}, I_S=1\text{A}, T_j=25^\circ\text{C}$	---	---	1	V

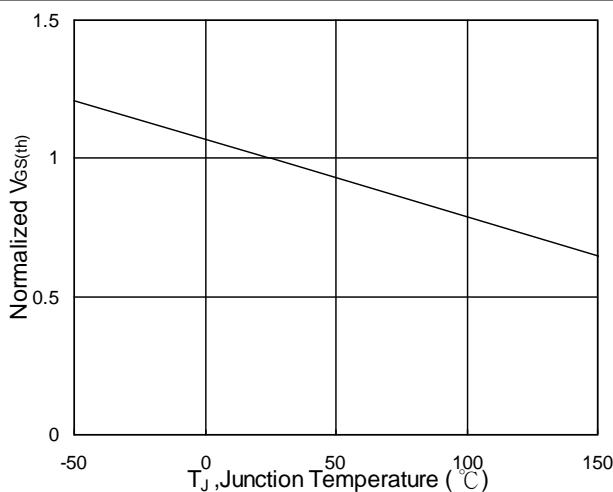
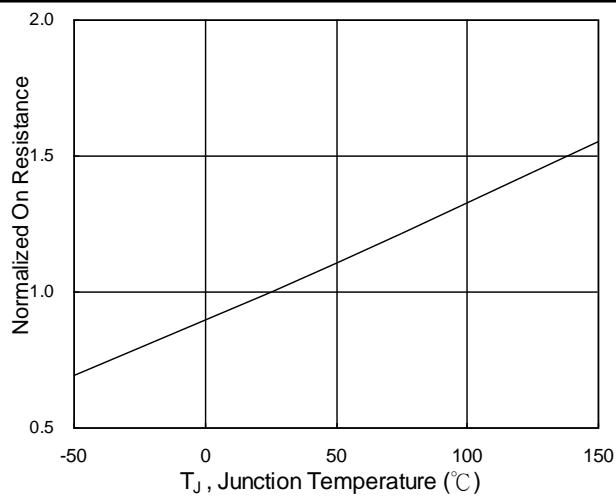
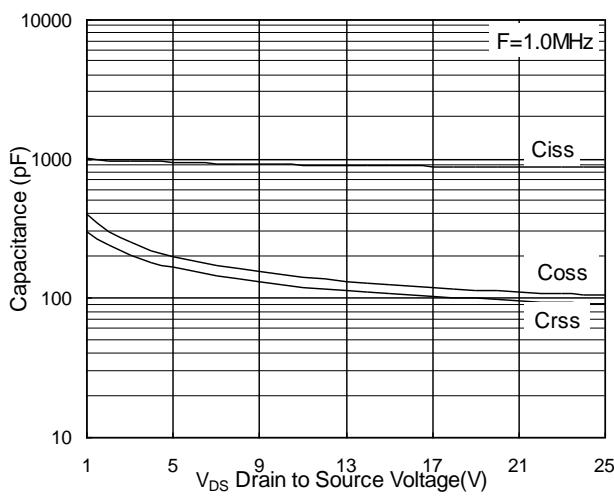
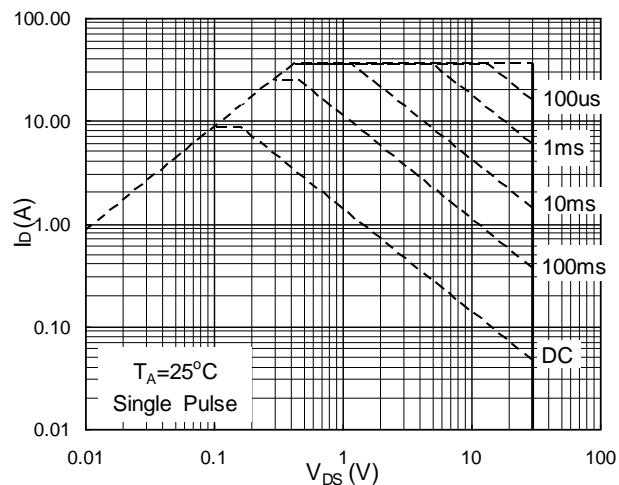
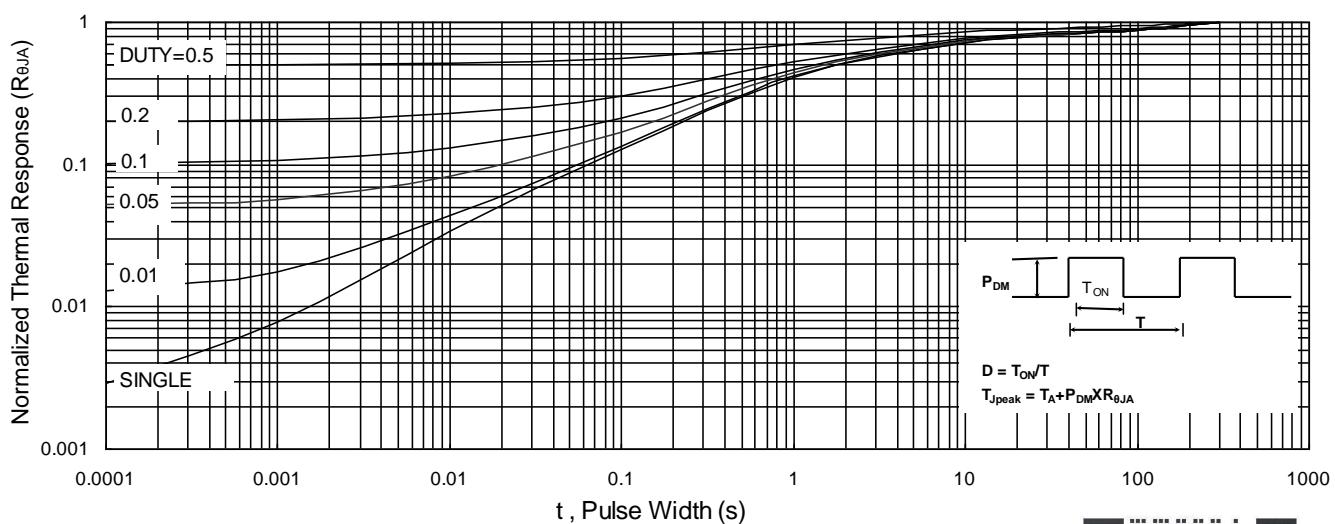


I_S	Continuous Source Current ^{1,5}	$V_G=V_D=0V$, Force Current	---	---	9	A
I_{SM}	Pulsed Source Current ^{2,5}		---	---	36	
T_{rr}	Body Diode Reverse Recovery Time	$I_F=8A$, $dl/dt=100A/\mu s$, $T_J=25^\circ C$	---	8	---	Ns
Q_{rr}	Body Diode Reverse Recovery Charge		---	2.9	---	Nc

Notes:

- 1.The data tested by surface mounted on a 1 inch² FR-4 board with 2OZ copper.
- 2.The data tested by pulsed , pulse width $\leq 300\mu s$, duty cycle $\leq 2\%$
- 3.The EAS data shows Max. rating . The test condition is $V_{DD}=25V$, $V_{GS}=10V$, $L=0.1mH$, $I_{AS}=22A$
- 4.The power dissipation is limited by $150^\circ C$ junction temperature
- 5.The data is theoretically the same as I_D and I_{DM} , in real applications , should be limited by total power dissipation.

Typical Characteristics:**Fig.1 Typical Output Characteristics****Fig.2 On-Resistance vs. G-S Voltage****Fig.3 Forward Characteristics of Reverse****Fig.4 Gate-Charge Characteristics**


Fig.5 Normalized $V_{GS(th)}$ vs. T_J

Fig.6 Normalized $R_{DS(on)}$ vs. T_J

Fig.7 Capacitance

Fig.8 Safe Operating Area

Fig.9 Normalized Maximum Transient Thermal Impedance
